Technical Session Schedule

	Wednesday December 12, 2007			
12:00 - 7:00 PM	***Registration - Grand Ballroom Lounge***			
Room	***Colony Ballroom***	***Margaret Brent***	***Jimenez***	***Carroll***
1:30–3:30 PM	**WP1**: Novel Device Structures	**WP2**: Space Application and Extreme Environments I	**WP3**: Oxides and Dielectrics I	**WP4**: Sensors and Biosensors
3:45–5:35 PM	**WP5**: Quantum Tunneling and Transport	**WP6**: Space Application and Extreme Environments II	**WP7**: Oxides and Dielectrics II	**WP8**: Modelling Gate Related Effects
6:00–8:30 PM	***Welcome Reception and Poster Session - Grand Ballroom***			
	Thursday December 13, 2007			
7:30 AM - 5:00 PM	***Registration - Grand Ballroom Lounge***			
Room	***Colony Ballroom***	***Banneker***	***Jimenez***	***Carroll***
8:00–10:00 AM	**TA1**: SiC Power Electronic Devices	**TA2**: Advanced Processing	**TA3**: Applications of Nanoscale Devices	**TA4**: Statistical and Technology Modeling
10:15–12:00 PM	**TA5**: Wide Bandgap Materials	**TA6**: Silicon on Insulator	**TA7**: Physics of Nanoelectronic Devices	**TA8**: Compact Modeling
12:00-1:00 PM	***Box Lunch -Grand Ballroom***			
1:00–3:30 PM	***Plenary Session - Colony Ballroom***			
3:45–5:45 PM	**TP1**: Performance and Reliability of III-Nitride RF Devices	**TP2**: Si/Ge Devices & Materials	**TP3**: MEMS	**TP4**: Device Simulations
6:15–9:15 PM	***Symposium Awards Banquet - Grand Ballroom***			
	Friday December 14, 2007			
Room	***Colony Ballroom***	***Banneker***	***Jimenez***	***Carroll***
8:00–10:00 AM	**FA1**: SiC MOS Technology and Issues	**FA2**: High Frequency I	**FA3**: Manufacturing Issues of Nanoelectronic Devices	**FA4**: Organic Materials and Devices
10:15–12:15 PM	**FA5**: Wide Bandgap Materials	**FA6**: High Frequency II	**FA7**: Novel Nanoscale Devices and Device Technologies	**FA8**: Flexible Electronics
12:15-1:15	***Lunch (on your own)***			
1:15–3:15 PM	**FP1**: Photodetectors and Memory Devices	**FP2**: Optoelectronics: New Detectors and Structures	**FP3**: Advanced Characterization and Testing I	
3:30–5:30 PM	**FP4**: Novel Circuits and Devices	**FP5**: Optoelectronics: New Lasers and Sources	**FP6**: Advanced Characterization and Testing II	